

but one of the tri-state drivers 120. As noted above, during the scan mode, test patterns are serially shifted through the scan chain 110. The shifting is indicated by assertion of the scan_enable signal. While the bits are shifted through the scan chain 110, the decoder 125 disables all of the tri-state drivers 120, except for one default driver 120α[d]. The foregoing prevents resource contention.

On page 9, Paragraph 0027:

[0027] If at 205, the circuit 100 is in the scan mode, all of the tri-state drivers 120 except for a default tri-state driver 120d for a shared resource 115 are disabled (210) during scan shifting (215). The decoder 125 disables the tri-state drivers 120 transmitting of a signal to the logic circuits 130 controlling each of the tri-state drivers 120 except the default tri-state driver 120α[d], causing the tri-state drivers 120 to be disabled. As noted above, the scan shifting is indicated by assertion of the scan_enable signal.

IN THE CLAIMS:

1. (Amended) A method for testing a circuit, said method comprising:

serially shifting a test pattern into at least a portion of the circuit;

disabling each of a plurality of tristate drivers except a default tristate driver from the plurality of tristate drivers while serially shifting;

capturing a test response from at least [a] the portion of the circuit; and